## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | ALFERNESS ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,560,231 B1	05-2003	Kawakami et al.	370/395.43
*	В	US-6,549,515 B1	04-2003	Sourani et al.	370/232
*	С	US-2004/0017781 A1	01-2004	Alferness et al.	370/252
*	D	US-6,067,301 A	05-2000	Aatresh, Deepak J.	370/418
*	Ε	US-6,144,638 A	11-2000	Obenhuber et al.	370/231
*	F	US-5,838,681 A	11-1998	Bonomi et al.	370/395.41
*	G	US-6,442,138 B1	08-2002	Yin et al.	370/232
*	Н	US-6,424,657 B1	07-2002	Voit et al.	370/412
*	1	US-6,249,528 B1	06-2001	Kothary, Piyush	370/466
*	J	US-2003/0007211 A1	01-2003	Gummalla et al.	359/136
	К	US-			
	٦	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
L.	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*	L	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.